



Atomic force microscopy

Measured values

- Surface profile and surface roughness of plane samples, especially optics

Principle

Surface scanning by the atomic force principle in contact or non-contact mode.
Maximum scanning area: 100x100µm²

Application

Investigation of surface fine structure with nm resolution

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This handout, and cross-references to related measurement techniques and facilities are available at: <http://messtec.dlr.de/link-515-en>.